


<b>Search Notes</b>  	<b>Application/Control No.</b>  10539400	<b>Applicant(s)/Patent Under Reexamination</b>  FUJIKAWA ET AL.
	<b>Examiner</b>  Hailey, Patricia L	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner
502	208, 210, 211, 213, 313-316	7/31/08	PLH

SEARCH NOTES		
Search Notes	Date	Examiner
Search updated from previous action (searching initiated 07/24/08); EAST search	7/31/08	PLH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner